

**Table 3.1** Summary of Important Equations

Quantity	Relationship	Values of Constants and Parameters (for Intrinsic Si at $T = 300$ K)
Carrier concentration in intrinsic silicon ( $\text{cm}^{-3}$ )	$n_i = BT^{3/2} e^{-E_g/2kT}$	$B = 7.3 \times 10^{15} \text{ cm}^{-3} \text{ K}^{-3/2}$ $E_g = 1.12 \text{ eV}$ $k = 8.62 \times 10^{-5} \text{ eV/K}$ $n_i = 1.5 \times 10^{10} / \text{cm}^3$
Diffusion current density ( $\text{A/cm}^2$ )	$J_p = -qD_p \frac{dp}{dx}$ $J_n = qD_n \frac{dn}{dx}$	$q = 1.60 \times 10^{-19} \text{ coulomb}$ $D_p = 12 \text{ cm}^2/\text{s}$ $D_n = 34 \text{ cm}^2/\text{s}$
Drift current density ( $\text{A/cm}^2$ )	$J_{\text{drift}} = q(p\mu_p + n\mu_n)E$	$\mu_p = 480 \text{ cm}^2/\text{V} \cdot \text{s}$ $\mu_n = 1350 \text{ cm}^2/\text{V} \cdot \text{s}$
Resistivity ( $\Omega \cdot \text{cm}$ )	$\rho = 1/[q(p\mu_p + n\mu_n)]$	$\mu_p$ and $\mu_n$ decrease with the increase in doping concentration
Relationship between mobility and diffusivity	$\frac{D_n}{\mu_n} = \frac{D_p}{\mu_p} = V_T$	$V_T = kT/q \simeq 25.9 \text{ mV}$
Carrier concentration in $n$ -type silicon ( $\text{cm}^{-3}$ )	$n_{n0} \simeq N_D$ $p_{n0} = n_i^2/N_D$	
Carrier concentration in $p$ -type silicon ( $\text{cm}^{-3}$ )	$p_{p0} \simeq N_A$ $n_{p0} = n_i^2/N_A$	
Junction built-in voltage (V)	$V_0 = V_T \ln\left(\frac{N_A N_D}{n_i^2}\right)$	
Width of depletion region (cm)	$\frac{x_n}{x_p} = \frac{N_A}{N_D}$ $W = x_n + x_p$ $= \sqrt{\frac{2\epsilon_s}{q} \left( \frac{1}{N_A} + \frac{1}{N_D} \right) (V_0 + V_R)}$	$\epsilon_s = 11.7\epsilon_0$ $\epsilon_0 = 8.854 \times 10^{-14} \text{ F/cm}$

Table 3.1 continued		
Quantity	Relationship	Values of Constants and Parameters (for Intrinsic Si at $T = 300$ K)
Charge stored in depletion layer (coulomb)	$Q_J = q \frac{N_A N_D}{N_A + N_D} AW$	
Forward current (A)	$I = I_p + I_n$ $I_p = Aqn_i^2 \frac{D_p}{L_p N_D} (e^{V/V_T} - 1)$ $I_n = Aqn_i^2 \frac{D_n}{L_n N_A} (e^{V/V_T} - 1)$	
Saturation current (A)	$I_S = Aqn_i^2 \left( \frac{D_p}{L_p N_D} + \frac{D_n}{L_n N_A} \right)$	
$I$ - $V$ relationship	$I = I_S (e^{V/V_T} - 1)$	
Minority-carrier lifetime (s)	$\tau_p = L_p^2/D_p \quad \tau_n = L_n^2/D_n$	$L_p, L_n = 1 \mu\text{m to } 100 \mu\text{m}$ $\tau_p, \tau_n = 1 \text{ ns to } 10^4 \text{ ns}$
Minority-carrier charge storage (coulomb)	$Q_p = \tau_p I_p \quad Q_n = \tau_n I_n$ $Q = Q_p + Q_n = \tau_T I$	
Depletion capacitance (F)	$C_{j0} = A \sqrt{\left( \frac{\epsilon_s q}{2} \right) \left( \frac{N_A N_D}{N_A + N_D} \right) \frac{1}{V_0}}$ $C_j = C_{j0} / \left( 1 + \frac{V_R}{V_0} \right)^m$	$m = \frac{1}{3} \text{ to } \frac{1}{2}$
Diffusion capacitance (F)	$C_d = \left( \frac{\tau_T}{V_T} \right) I$	